Automatic Surface Analysis System

- Fully automated, unattended, SIMS analysis
- Large X-Y sample stage
- Oxygen ion gun for high sensitivity analysis
- Customisable cassette style sample holder
- Parameters can be specified via spreadsheet
- 3D characterisation
- Nanometre depth resolution
- Modular servicing for high up-time

Deposition Rate Monitor for Molecular Beam Analysis & Deposition Control

- High sensitivity, enhanced detection from 100% to 5 ppb
- 320 or 510 amu mass range
- Detection limits down to 30 ions/second in molecular beam studies
- Monitor growth rates of 1 Å/minute and lower
- Cross beam ion source with beam apertures configured for multiple beam positions
- Integral UHV compatible water-cooled shroud

High Sensitivity Surface Analysis for In-Situ Substrate Characterisation and Contamination Studies

- Pre-growth substrate purity analysis
- Elemental surface mapping
- 3D depth profiling
- Excellent sensitivity and dynamic range
- Customised software interface for SIMS
- ‘Feature MS’ mode allows mass spectral data to be gained from a specific area of interest, for example a contaminant or grain boundary

RGA Analyser for MBE Chambers

- Vacuum diagnostics
- Leak detection
- Vacuum fingerprint analysis
- 200 amu mass range
- Dual Faraday/Electron multiplier detectors
- Contamination resistant source shroud
- Molybdenum wiring in place of copper wiring to improve lifetime in MBE environments

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